

## Talk 4: Present and Future Perspectives for High-Energy Ion Testing

*Thursday, 13 June 2024 15:15 (20 minutes)*

### Abstract:

As the complexity of electronic devices increases (artificial intelligence, big-data processing applications, 3D integrated devices, etc.) and new space advances, the paradigms for single event testing are evolving. In particular, one of the areas of strong interest is the use of high-energy heavy ion beams. The aim of this contribution is to discuss the motivations, requirements, and future perspectives for high-energy ion testing and facilities.

### CV:

Marta Bagatin graduated in Electronics Engineering in 2006 (summa cum laude) and received a Ph.D. in Information Science and Technology in 2010 from the University of Padova, Italy. Since September 2022, she is an Associate Professor in Electronics at the University of Padova.

Her research interests concern the experimental study and modeling of radiation effects and reliability issues on electronic devices for space, nuclear, and terrestrial applications, with a special focus on non-volatile semiconductor memories. Marta is the author or co-author of 4 book chapters, more than 80 papers published in peer-reviewed journals, more than 90 presentations at international conferences, and editor of one book. She was a lecturer or invited speaker for seminars and lectures at universities, research centers, space agencies, and companies in Europe, USA, Brazil, China, and Australia.

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**Session Classification:** Session 6: Protons and Heavy ions: The User's Perspective